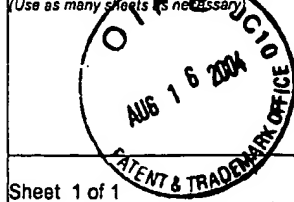


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Complete if Known	
Application Number	09/834,751
Filing Date	April 13, 2001
First Named Inventor	Velichko, Sergey
Group Art Unit	2857
Examiner Name	Miller, Craig
Attorney Docket No: 303.750US1	

Sheet 1 of 1

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Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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EXAMINER

DATE CONSIDERED

10/25/04

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PTO/SB/06A(10-01)
 Approved for use through 10/31/2002. OMB 581-0001
 US Patent & Trademark Office, U.S. DEPARTMENT OF COMMERCE

Complete if Known

Application Number 09/834751
 Filing Date April 13, 2001
 First Named Inventor Velichko, Sergey
 Group Art Unit 2812
 Examiner Name Miller, Craig

Attorney Docket No: 303.750US1

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